

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination SANDA ET AL.	
		Examiner Evan Pert	Art Unit 2829	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6819117 B2	11-2004	Wilsher	324/601
	B	US-6608494 B1	08-2003	Bruce et al.	324/752
	C	US-6596980 B2	07-2003	Rusu et al.	250/214.1
	D	US-			
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Weger et al., "Transmission Line Pulse Picosecond Imaging Circuit Analysis Methodology for Evaluation of ESD and Latchup", March 30, 2004, 41st Annual 2003 IEEE International Reliability Physics Symposium Proceedings, pages 99-104.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.